

## Status in the past 3 years

Simulation side:
> Prediction of performance of the gating foil under higher $B$. (+ understanding of behavior )
$>$ Simulation did not fit with data under B.
$>$ Behavior under $B$ is very suspicious.

Experimental side:
Comparison of Electron transmission between Exp. and Sim.

Exp vs Sim (Fujikura Type 3)

> A method for evaluating transmission has been modified:

Using only an open state data.
Two data set (normal/reverse voltage of Edrift) are not necessary.
http://www-jlc.kek.jp/jlc/sites/default/files/7.27SagaYamashita.pptx

## Geometries for the simulation

Smooth
trapezoidal


Not smooth trapezoidal It seems to have protrusions..

Geometry parameters Measurement results

|  | Rim width (um) |  | Copper thickness(um) |  |
| :---: | :---: | :---: | :---: | :---: |
|  | F-side | B-side | F-side | B-side |
| Ave. | 26.74 | 30.96 | 9.20 | 2.83 |
| Max-Min | 6.87 | 7.27 | 3.19 | 0.89 |
| $3 \sigma$ | 4.66 | 5.03 | 2.33 | 0.69 |

Daisuke Arai (presented at MPGD2015)

| Item | Gating foil |
| :---: | :---: |
| Hole size | $304 \mu \mathrm{~m}$ |
| Hole pitch | $335 \mu \mathrm{~m}$ |
| Rim width : F-side | $27 \mu \mathrm{~m}$ |
| Rim width : B-side | 31 um |
| Insulator thickness | $12.5 \mu \mathrm{~m}$ |
| size | 100 mm x 100 mm |
| Processing time | 70 min (only laser) |
| Optical aperture ratio | $82.3 \%$ |



## Simulation

## Avalanche Microscopic,

 with the "default" setting originally implemented in garfield

## Ikematsu

Exp vs Sim (Fujikura Type 3)



## Simulation

## Avalanche Microscopic, with "Null collision steps"

originally implemented in garfield

There is a switch on "Null collision steps"
E-field is updated
in each step after sampling time $\Delta t$ even if the step is null-collision.
According to a developer this was supposed that more precise tracking is given.


## Simulation: AvalancheMicrosopic

Avalanche Microscopic function,
1). An electron trajectory is calculated based on given sampling time $\Delta \mathbf{t}(=-<\tau>\log (\mathbf{u}) \mathbf{u}[0,1])$,
2). Electron kinetic energy $\varepsilon^{\prime}$ after $\Delta t$ is evaluated

$$
\epsilon^{\prime}=\epsilon+q \mathbf{v} \cdot \mathbf{E} \Delta t+\frac{q^{2}}{2 m_{e}} \mathbf{E}^{2} \Delta t^{2}
$$

A change of the kinetic energy after $\Delta t$
$v$ and $E$ do not have time dependence, initial information are continuously used during $\Delta t$
(acceleration and deceleration are not sufficient.)
In reality,
E-field dramatically varies. especially at around geometry.
v and E should be time-dependent variables like $\mathrm{v}(\mathrm{t})$ and $\mathrm{E}(\mathrm{r}(\mathrm{t})$ ),


## Simulation: AvalancheMicrosopic w/ sub-step

Avalanche Microscopic function,
1). An electron trajectory is calculated based on given sampling time $\Delta \mathbf{t}(=-<\tau>\log (\mathbf{u}) \mathbf{u}[0,1])$,
p22~p25
2). Electron kinetic energy $\varepsilon^{\prime}$ after $\Delta t$ is evaluated

$$
\epsilon^{\prime}=\epsilon+q \mathbf{v} \cdot \mathbf{E} \Delta t+\frac{q^{2}}{2 m_{e}} \mathbf{E}^{2} \Delta t^{2}
$$

change of the kinetic energy after $\Delta t$
Defined sub-step time $\delta \mathrm{t} \quad \delta t(=\Delta t / N) \quad$ recover above First approximation with $\mathrm{N}=1$

$$
\begin{aligned}
& \epsilon^{\prime}=\epsilon+\sum_{i}^{N} \underbrace{q \boldsymbol{v}_{i}\left(\boldsymbol{E}_{i-1}, \delta t_{i}\right)}_{\text {time dependent v }} \cdot \underset{\text { time dependent } \mathrm{E}}{\boldsymbol{\boldsymbol { E } _ { i }}\left(\boldsymbol{r}_{i-1}\left(\delta t_{i-1}\right)\right) \delta t_{i}} \\
& +\sum_{i}^{N} \frac{q^{2}}{2 m_{e}} \boldsymbol{E}_{i}\left(\boldsymbol{r}_{i-1}\left(\delta t_{i-1}\right)\right)^{2} \delta t_{i}^{2} \\
& v \text { depends on } E \text { and } \delta t \\
& E \text { depends on } r \\
& r \text { depends on } \delta t
\end{aligned}
$$

A program has to access a field map many times Huge CPU consumption and time is necessary.

If the field map is precisely generated, more time is needed

## Simulation: AvalancheMicrosopic w/ sub-step approx.

Avalanche Microscopic function,
1). An electron trajectory is calculated based on given sampling time $\Delta \mathbf{t}(=-<\tau>\log (\mathbf{u}) \mathbf{u}[0,1])$,
p22~p25
2). Electron kinetic energy $\varepsilon^{\prime}$ after $\Delta t$ is evaluated

$$
\epsilon^{\prime}=\epsilon+q \mathbf{v} \cdot \mathbf{E} \Delta t+\frac{q^{2}}{2 m_{e}} \mathbf{E}^{2} \Delta t^{2}
$$

change of the kinetic energy after $\Delta t$
Defined sub-step time $\delta \mathrm{t} \quad \delta t(=\Delta t / N) \quad$ recover above First approximation with $\mathrm{N}=1$
I check $E^{\prime}(v($ initial $) * \Delta t)$

$$
d \boldsymbol{E}=\underset{\text { initial }}{\boldsymbol{E}}-\boldsymbol{E}^{\prime} \quad \longrightarrow \mathrm{tter} \Delta \mathrm{t} \quad \longrightarrow \quad \begin{gathered}
\text { continuously include } \\
\text { the variation as }
\end{gathered} \quad \boldsymbol{E}-\frac{d \boldsymbol{E}}{N} i
$$

$$
\begin{aligned}
\epsilon^{\prime}=\epsilon & +\sum_{i}^{N} \frac{q \boldsymbol{v}_{i}\left(\boldsymbol{E}-\frac{d \boldsymbol{E}}{N} i, \delta t_{i}\right)}{\text { time dependent } \mathrm{v}} \cdot\left(\boldsymbol{E}-\frac{d \boldsymbol{E}}{N} i\right) \delta t_{i} \\
& +\sum_{i}^{N} \frac{q^{2}}{2 m_{e}}\left(\boldsymbol{E}-\frac{d \boldsymbol{E}}{N} i\right)^{2} \delta t_{i}^{2}
\end{aligned}
$$

Under the assumption : the variation of the E-field b/w $\mathbf{E}(\mathbf{r})$ and $\mathbf{E}^{\prime}\left(\mathbf{r}^{\mathbf{s}}\right)$ (within $\Delta \mathrm{t}$ ) is linearly changed.

## Simulation w/ sub-step approx.



## Simulation w/ sub-step




## Another simulation is the closed state

## Ion blocking measurement ( exp. data is with an electron )

$\rightarrow$ The key point is diffusion.

$$
\begin{aligned}
& \text { t2k@ 0.0T e- } \sim 300 \mu \mathrm{~m} / \sqrt{ } \mathrm{cm} \text { (Magboltz.) 230v/cm } \\
& \text { Ar }+ \text {, } \mathrm{iC} 4 \mathrm{H} 10+\sim 142 \mu \mathrm{~m} / \sqrt{ } \mathrm{cm} \text { (textbook, Dt }{ }^{\wedge} 2 \sim 1 / E-f i e l d \\
& \text { an ion has thermal energy } \\
& \frac{D_{\mathrm{T}}(\omega)}{D_{\mathrm{T}}(0)}=\frac{1}{1+\omega^{2} \tau^{2}}, \quad \text { textbook } \\
& \omega \tau=B \mu \simeq \begin{cases}10^{-4} & \text { for ions } \\
1 & \text { for electrons }\end{cases} \\
& \omega \text { :cyclotron frequency } \\
& \tau \text { : mean free time } \\
& \text { Dt of the ion does not change under } \mathrm{B} \\
& \rightarrow \mathrm{~B}=0 \text { give enough prediction } \\
& \text { for the ion blocking, } \\
& \text { Exp. with the electron. } \\
& \text { can give the lower limit for the ion blocking } \\
& \text { The modified version gives similar result } \\
& \text { (electron) }
\end{aligned}
$$

## Summary

Simulation was modified for predictions of the behavior of the gating foil
( I need to have discussion with a developer )
The Results reproduce experiment to some extent for 0 and 1 T .
With $0-1 \mathrm{~V}$ operation the transmission of $>80 \%$ is
PROBABLY achievable under $\sim 3.5 / 4.0 \mathrm{~T}$.
Simulation indicate that ion blocking of $<10^{\wedge}-5$ even for $<10^{\wedge}-6$ is
PROBABLY achievable for a higher B field with the applied voltage of $<-20 \mathrm{~V}$.

Remaining tasks are 1). direct measurement of ion blocking using the ion itself. and compare with the simulation (confirmation).
2). actual measurement under the higher $B$ field. (electron/ion)

Ratio reaching to the dielectric


Ratio reaching to a lower copper




